

ON Semiconductor®

FDS6679AZ P-Channel PowerTrench[®] MOSFET -30V, -13A, $9m\Omega$

General Description

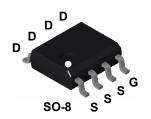
This P-Channel MOSFET is producted using ON Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance.

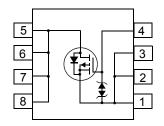
This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)}$ = 9.3m Ω at V_{GS} = -10V, I_D = -13A
- Max $r_{DS(on)}$ = 14.8m Ω at V_{GS} = -4.5V, I_D = -11A
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 6kV typical (note 3)
- High performance trench technology for extremely low 「FDS(on)
- High power and current handing capability
- RoHS Compliant





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Parameter Ratings						
V_{DS}	Drain to Source Voltage		Drain to Source Voltage		Drain to Source Voltage		-30	V
V_{GS}	Gate to Source Voltage		±25	V				
	Drain Current -Continuous	(Note 1a)	-13	۸				
ID	-Pulsed		-65	Α				
	Power Dissipation for Single Operation	(Note 1a)	2.5					
P_{D}		(Note 1b)	1.2	W				
		(Note 1c)	1.0					
T _J , T _{STG}	Operating and Storage Temperature		-55 to +150	°C				

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance , Junction to Ambient (Note 1a)	50	°C/W
$R_{\theta JC}$	Thermal Resistance , Junction to Case (Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDS6679AZ	FDS6679AZ	13"	12mm	2500 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

Off Characteristics							
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A$, $V_{GS} = 0 V$	-30			V	
$\frac{\Delta B_{VDSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		-20		mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -24V, V _{GS} =0V			-1	μΑ	
I _{GSS}	Gate to Source Leakage Current	V_{GS} = ±25V, V_{DS} =0V			±10	μΑ	

Test Conditions

Min

Тур

Max

Units

On Characteristics (Note 2)

Symbol

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1	-1.9	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		6.5		mV/°C
r _{DS(on)}	Drain to Source On Resistance	$V_{GS} = -10V, I_D = -13A$		7.7	9.3	- mΩ
		$V_{GS} = -4.5V$, $I_D = -11A$		11.8	14.8	
		$V_{GS} = -10V, I_D = -13A,$ $T_J = 125^{\circ}C$		10.7	13.4	
9 _{FS}	Forward Transconductance	$V_{DS} = -5V, I_{D} = -13A$		55		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = -15V, V _{GS} = 0V, f = 1MHz	2890	3845	pF
C _{oss}	Output Capacitance		500	665	pF
C _{rss}	Reverse Transfer Capacitance		495	745	pF

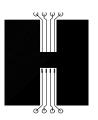
Switching Characteristics (Note 2)

t _{d(on)}	Turn-On Delay Time		13	24	ns
t _r	Rise Time	$V_{DD} = -15V, I_{D} = -1A$ $V_{GS} = -10V, R_{GS} = 6\Omega$	15	27	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = -10V, K _{GS} = 012	210	336	ns
t _f	Fall Time		92	148	ns
Qg	Total Gate Charge	$V_{DS} = -15V, V_{GS} = -10V,$ $I_{D} = -13A$	68	96	nC
Q_g	Total Gate Charge	V 45V V 5V	38	54	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = -15V, V_{GS} = -5V,$ $I_{D} = -13A$	10		nC
Q_{gd}	Gate to Drain Charge		17		nC

Drain-Source Diode Characteristic

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = -2.1A$	-0.7	-1.2	V
t _{rr}	Reverse Recovery Time	$I_F = -13A$, $di/dt = 100A/\mu s$		40	ns
Q _{rr}	Reverse Recovery Charge	$I_F = -13A$, di/dt = 100A/ μ s		-31	nC

13 R_{B,IA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{B,C} is guaranteed by design while R_{B,CA} is determined by the user's board design.



a) 50°C/W when mounted on a 1 in² pad of 2 oz copper



b)105°C/W when mounted on a .04 in² pad of 2 oz copper



c) 125°C/W when mounted on a minimun pad

Scale 1: 1 on letter size paper

- 2: Pulse Test:Pulse Width <300 μ s, Duty Cycle <2.0%
- 3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25°C unless otherwise noted

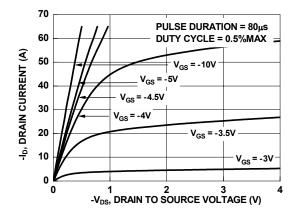


Figure 1. On Region Characteristics

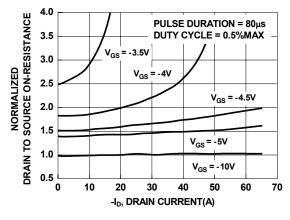


Figure 2. Normalized On-Resistance vs Drain **Current and Gate Voltage**

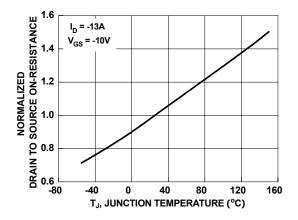


Figure 3. Normalized On Resistance vs Junction **Temperature**

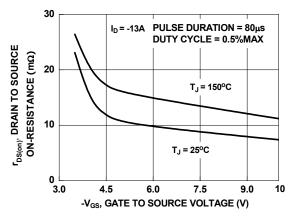


Figure 4. On-Resistance vs Gate to Source Voltage

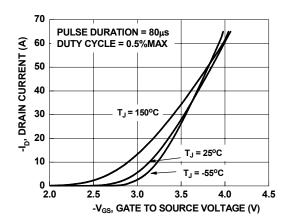


Figure 5. Transfer Characteristics

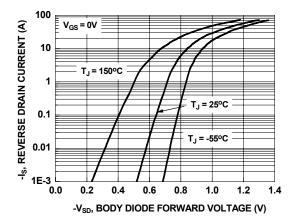


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



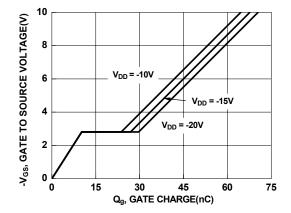


Figure 7. Gate Charge Characteristics

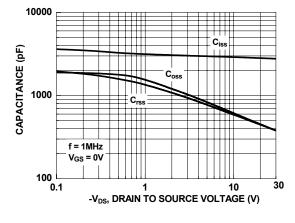


Figure 8. Capacitance vs Drain to Source Voltage

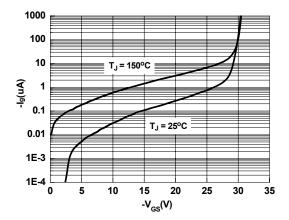


Figure 9. $I_g vs V_{GS}$

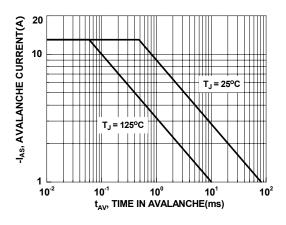


Figure 10. Unclamped Inductive Switching Capability

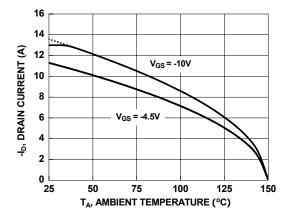


Figure 11. Maximum Continuous Drain Current vs
Ambient Temperature

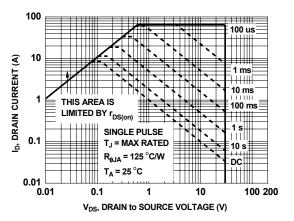


Figure 12. Forward Bias Safe Operating Area



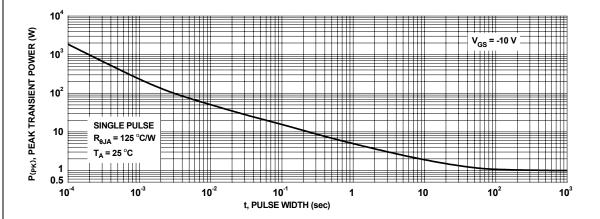


Figure 13. Single Pulse Maximum Power Dissipation

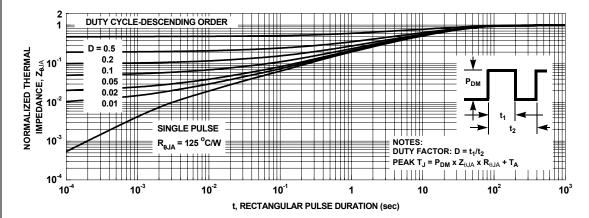


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hol

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Phone: 421 33 790 2910

Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative